good memories start here

MTS800 – SATA III 6Gb/s M.2 SSD

Transcend MTS800 series are M.2 SSDs with high performance and quality Flash Memory assembled on a printed circuit board. These M.2 SSDs feature cutting-edge technology to enhance product life and data retention. MTS800 is designed specifically for various applications such as Ultrabooks, industrial PCs, vehicle PCs and road surveillance recording.

- Power Supply: 3.3V±5%
- Fully compatible with devices and OS that support the SATA III 6.0Gb/s standard
- Compliant with M.2 standards in SATA specification

Features

- Advanced global wear-Leveling and block
 management for reliability
- Built-in ECC (Error Correction Code) functionality
- Features a DDR3 DRAM cache
- Supports Advanced Garbage Collection
- Supports enhanced S.M.A.R.T. function
- Real time full drive encryption with Advanced Encryption Standard (AES) (Optional)
- Power Shield to prevent data loss in the event of a sudden power outage
- Supports partial and slumber mode
- Supports security command
- Supports Hardware purge and write protect (Optional)
- Supports Transcend SSD scope pro (Optional)
- RoHS compliant



Specifications

| Physical Specification | | | | | |
|------------------------|--------|--------------------------|-----------------------------|--|--|
| Form Factor | | M.2 TYPE 2280-D2-B-M | | | |
| Storage Capacities | | 32~512GB | | | |
| Length | | $80.00\pm0.15~\text{mm}$ | $3.150\pm0.006~\text{inch}$ | | |
| Dimensions | Width | $22.00\pm0.15~\text{mm}$ | $0.866\pm0.006\text{ inch}$ | | |
| | Height | $3.50\pm0.15~\text{mm}$ | $0.138\pm0.006\text{ inch}$ | | |
| Input Voltage | | $3.3V \pm 5\%$ | | | |
| Weight | | $9 \text{ g} \pm 5\%$ | | | |
| Connector | | M.2 module notch B+M | | | |

| Environmental Specifications | | | | | |
|------------------------------|---------------|----------------------------|--|--|--|
| Operating Temperature | | -10 °C to 80 °C | | | |
| Storage Temperature | | -40 ℃ to 85 ℃ | | | |
| Humidity | Operating | 0% to 95% (Non-condensing) | | | |
| Humidity | Non-Operating | 0% to 95% (Non-condensing) | | | |

| Performance | | | | | | | | |
|-----------------|--------------|---------------|----------------------|-----------------------|-----------------------------|---------------------------------|--------------------------------------|---------------------------------------|
| | ATTO | | | CrystalDiskMark | | | IOMeter | |
| Model P/N | Max Read* | Max Write* | Sequential Read** | Sequential Write** | Random Read (4KB QD32)** | Random Write (4KB QD32)** | IOPS Random Read (4KB QD32)*** | IOPS Random Write (4KB QD32)*** |
| TS32XBTMM0000A | 230 | 40 | 230 | 40 | 90 | 40 | 20K | 10K |
| TS64XBTMM0000A | 450 | 80 | 440 | 80 | 170 | 80 | 40K | 20K |
| TS128XBTMM0000A | 540 | 170 | 520 | 160 | 270 | 160 | 70K | 40K |
| TS256XBTMM0000A | 550 | 320 | 520 | 320 | 300 | 300 | 75K | 75K |
| TS512XBTMM0000A | 550 | 460 | 520 | 460 | 290 | 310 | 70K | 75K |

Note: Maximum transfer speed recorded

* 25 °C, test on GIGABYTE GA-Z87X-D3H, 4GB, Windows® 7 Professional with AHCI mode, benchmark utility ATTO (version 2.41), unit MB/s

** 25 °C, test on GIGABYTE GA-Z87X-D3H, 4GB, Windows® 7 Professional with AHCI mode, benchmark utility CrystalDiskMark (version 3.0.1), copied file 1000MB, unit MB/s

*** 25 °C, test on GIGABYTE GA-Z87X-D3H, 4GB, Windows® 7 Professional with AHCI mode, benchmark utility IOmeter2006 with 4K file size and queue depth of 32, unit IOPs **** The recorded performance is obtained while the SSD is not operating as an OS disk Physical Specification



| Actual Capacity | | | | | | |
|-----------------|---------------|----------|------|--------|--|--|
| Model P/N | User Max. LBA | Cylinder | Head | Sector | | |
| TS32XBTMM0000A | 62,533,296 | 16,383 | 16 | 63 | | |
| TS64XBTMM0000A | 125,045,424 | 16,383 | 16 | 63 | | |
| TS128XBTMM0000A | 250,069,680 | 16,383 | 16 | 63 | | |
| TS256XBTMM0000A | 500,118,192 | 16,383 | 16 | 63 | | |
| TS512XBTMM0000A | 1,000,215,216 | 16,383 | 16 | 63 | | |

| Power Consumption | | | | | |
|--------------------------|-----------|----------------|--|--|--|
| Input Voltage | | $3.3V \pm 5\%$ | | | |
| Model P/N / Power Consum | nption | Average (mA) | | | |
| | Max Write | 236 | | | |
| TS32XBTMM0000A | Max Read | 226 | | | |
| | Idle | 75 | | | |
| | Max Write | 335 | | | |
| TS64XBTMM0000A | Max Read | 243 | | | |
| | ldle | 76 | | | |
| | Max Write | 508 | | | |
| TS128XBTMM0000A | Max Read | 244 | | | |
| | Idle | 76 | | | |
| | Max Write | 660 | | | |
| TS256XBTMM0000A | Max Read | 292 | | | |
| | Idle | 81 | | | |
| | Max Write | 661 | | | |
| TS512XBTMM0000A | Max Read | 300 | | | |
| | ldle | 82 | | | |

*Tested with IOmeter running sequential reads/writes and idle mode



| Reliability | | | | | |
|-------------------------------|---------------------------------------|----------|--|--|--|
| Data Reliability | Supports BCH ECC 60 bit per 1024 byte | | | | |
| MTBF | 1,500,000 hours | | | | |
| | 32G | 45 (TB) | | | |
| | 64G | 80 (TB) | | | |
| Endurance (Terabytes Written) | 128G | 150 (TB) | | | |
| | 256G | 280 (TB) | | | |
| | 512G | 550 (TB) | | | |

*Tested under JESD218A endurance test method and JESD219A endurance workloads specification.

| Vibration | | | | |
|---------------|-----------------|--|--|--|
| Operating | 3.0G, 5 - 800Hz | | | |
| Non-Operating | 5.0G, 5 - 800Hz | | | |

Reference to IEC 60068-2-6 Testing procedures; Operating-Sine wave, 5-800Hz/1 oct., 1.5mm, 3g, 0.5 hr./axis, total 1.5 hrs.

| Shock | |
|---------------|--------------|
| Operating | 1500G, 0.5ms |
| Non-Operating | 1500G, 0.5ms |

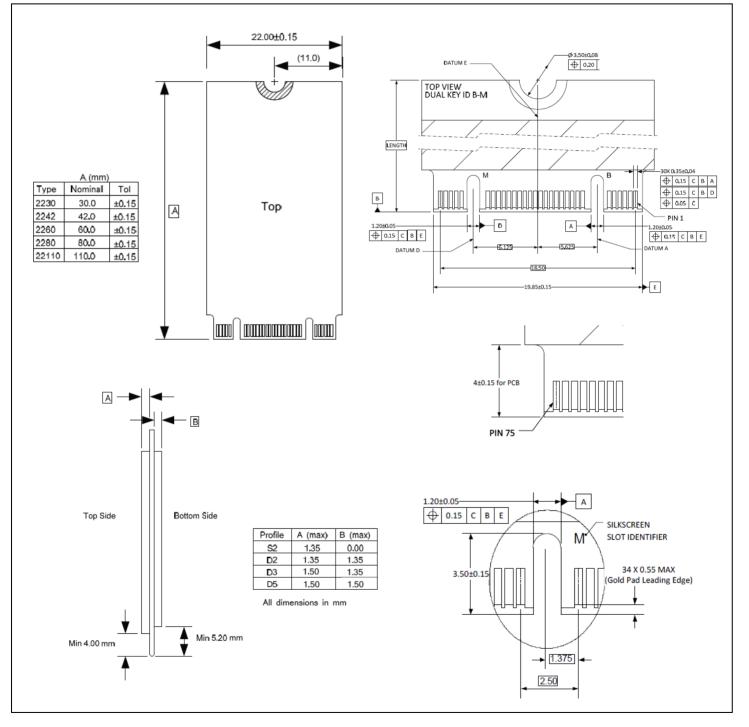
Reference to IEC 60068-2-27 Testing procedures; Operating-Half-sine wave, 1500G, 0.5ms, 3 times/dir., total 18 times.

| Regulations | |
|-------------|------------------|
| Compliance | CE, FCC and BSMI |



Package Dimensions

The figure below illustrates the Transcend M.2 Type 2280-D2-B-M Solid State Drive. All dimensions are in mm.



Pin Assignments

| Pin No. | Pin Name | Pin No. | Pin Name | Pin No. | Pin Name | Pin No. | Pin Name |
|---------|-----------|---------|-----------|---------|-----------|---------|----------|
| 01 | CONFIG_3* | 02 | 3.3V | 39 | GND | 40 | NC |
| 03 | GND | 04 | 3.3V | 41 | TX+ | 42 | NC |
| 05 | NC | 06 | NC | 43 | TX- | 44 | NC |
| 07 | NC | 08 | NC | 45 | GND | 46 | NC |
| 09 | NC | 10 | DAS/DSS** | 47 | RX- | 48 | NC |
| 11 | NC | 12 | NOTCH | 49 | RX+ | 50 | NC |
| 13 | NOTCH | 14 | NOTCH | 51 | GND | 52 | NC |
| 15 | NOTCH | 16 | NOTCH | 53 | NC | 54 | NC |
| 17 | NOTCH | 18 | NOTCH | 55 | NC | 56 | MFG1**** |
| 19 | NOTCH | 20 | NC | 57 | GND | 58 | MFG2**** |
| 21 | CONFIG_0* | 22 | NC | 59 | NOTCH | 60 | NOTCH |
| 23 | NC | 24 | NC | 61 | NOTCH | 62 | NOTCH |
| 25 | NC | 26 | NC | 63 | NOTCH | 64 | NOTCH |
| 27 | GND | 28 | NC | 65 | NOTCH | 66 | NOTCH |
| 29 | NC | 30 | NC | 67 | NC | 68 | NC |
| 31 | NC | 32 | NC | 69 | CONFIG_1* | 70 | 3.3V |
| 33 | GND | 34 | NC | 71 | GND | 72 | 3.3V |
| 35 | NC | 36 | NC | 73 | GND | 74 | 3.3V |
| 37 | NC | 38 | DEVSLP*** | 75 | CONFIG_2* | | |

* For SATA application, these pins connect to GND internally

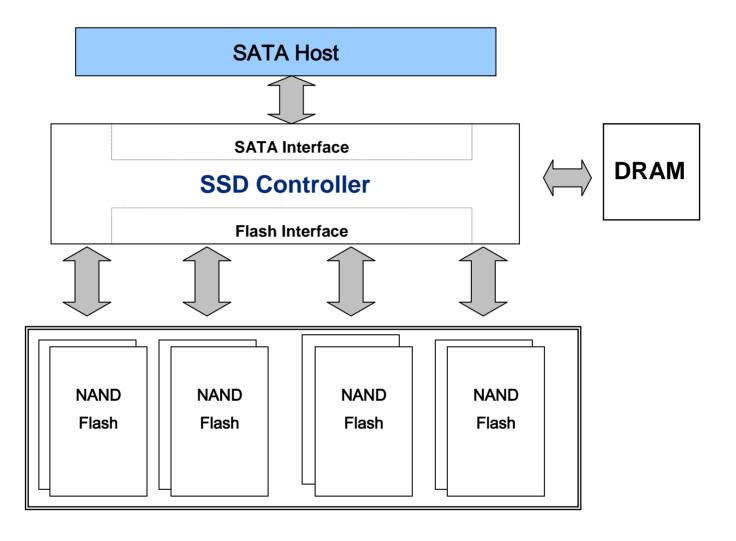
** Device Activity Signal / Disable Staggered Spin-up

*** Device Sleep, Input. If driven high the host is informing the SSD to enter a low power state

**** Manufacturing pins. Do not connect



Block Diagram





Features

• Global Wear Leveling – Advanced algorithms to enhance wear-leveling efficiency.

Global wear leveling ensures that every block has an even erase count. This helps to extend the life expectancy of an SSD.

There are three main processes in global wear leveling:

- Record the block erase count and save this in the wear-leveling table.
- Find the static-block and save this in the wear-leveling pointer.
- Check the erase count when a block is pulled from the pool of spare blocks. If the block erase count is larger than WEARCNT, then swap the static-block and over-count-block.

• ECC Algorithm

The controller uses BCH 40 Bit ECC algorithm per 1024 bytes depending on the structure of the flash. BCH40 may correct up to 40 random error bits within 1024 data bytes. With the help of BCH40 ECC, the endurance of Transcend SSD is greatly improved.

Bad Block Management

When the flash encounters ECC failed, program fail or erase fail, the controller will mark the block as a bad block. This will prevent the usage of bad blocks which may result in data loss in the future.

Advanced Garbage Collection

Transcend SSD has perfect garbage collection mechanism to help SSD improve performance. Advanced Garbage collection can efficiently manage memory management to let SSD can always has stable performance. With Transcend advanced flash management, the drive can still keep high performance after long time operation

• Enhanced S.M.A.R.T. function

Transcend SSD supports S.M.A.R.T. command (Self-Monitoring, Analysis, and Reporting Technology) that allows the user to read the health information of the SSD. Transcend also define some innovated S.M.A.R.T. features which allows the user to evaluate the status of the SSD in a much more efficient way.

Power Shield

The controller uses internal power shield circuit to prevent SSD from damage when a sudden power outage occurs. The SSD's internal power detect mechanism can monitor power provided by host. When a sudden power outage happens, the SSD can execute power shield mechanism to protect data in the SSD.

Hardware Purge and Write Protect

The SSD has optional features which include hardware trigger for quick data erase and write protect. These features may be enabled by simply connecting a switch to the designated pins.

StaticDataRefresh Technology



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Normally, ECC engine corrections are taken place without affecting the host normal operations. As time passes by, the number of error bits accumulated in the read transaction exceeds the correcting capability of the ECC engine, resulting in corrupted data being sent to the host. To prevent this, the controller monitors the error bit levels at each read operation; when it reaches the preset threshold value, the controller automatically performs data refresh to "restore" the correct charge levels in the cell. This implementation practically restores the data to its original, error-free state, and hence, lengthening the life of the data.



ATA Command Register

This table and the following paragraphs summarize the ATA command set.

| Command Table | | | | | | |
|----------------------------------|------------|-------------------|--|--|--|--|
| Support ATA/ATAPI Command | Code | Protocol | | | | |
| General Feature Set | | | | | | |
| EXECUTE DIAGNOSTICS | 90h | Device diagnostic | | | | |
| FLUSH CACHE | E7h | Non-data | | | | |
| IDENTIFY DEVICE | ECh | PIO data-In | | | | |
| Initialize Drive Parameters | 91h | Non-data | | | | |
| READ DMA | C8h | DMA | | | | |
| READ LOG Ext | 2Fh | PIO data-In | | | | |
| READ MULTIPLE | C4h | PIO data-In | | | | |
| READ SECTOR(S) | 20h | PIO data-In | | | | |
| READ VERIFY SECTOR(S) | 40h or 41h | Non-data | | | | |
| SET FEATURES | EFh | Non-data | | | | |
| SET MULTIPLE MODE | C6h | Non-data | | | | |
| WRITE DMA | Cah | DMA | | | | |
| WRITE MULTIPLE | C5h | PIO data-out | | | | |
| WRITE SECTOR(S) | 30h | PIO data-out | | | | |
| NOP | 00h | Non-data | | | | |
| READ BUFFER | E4h | PIO data-In | | | | |
| WRITE BUFFER | E8h | PIO data-out | | | | |
| Power Management Feature Set | | | | | | |
| CHECK POWER MODE | E5h or 98h | Non-data | | | | |
| IDLE | E3h or 97h | Non-data | | | | |
| IDLE IMMEDIATE | E1h or 95h | Non-data | | | | |
| SLEEP | E6h or 99h | Non-data | | | | |
| STANDBY | E2h or 96h | Non-data | | | | |
| STANDBY IMMEDIATE | E0h or 94h | Non-data | | | | |
| Security Mode Feature Set | | | | | | |
| SECURITY SET PASSWORD | F1h | PIO data-out | | | | |
| SECURITY UNLOCK | F2h | PIO data-out | | | | |
| SECURITY ERASE PREPARE | F3h | Non-data | | | | |
| SECURITY ERASE UNIT | F4h | PIO data-out | | | | |
| SECURITY FREEZE LOCK | F5h | Non-data | | | | |
| SECURITY DISABLE PASSWORD | F6h | PIO data-out | | | | |
| SMART Feature Set | | | | | | |
| SMART Disable Operations | B0h | Non-data | | | | |
| SMART Enable/Disable Autosave | B0h | Non-data | | | | |
| SMART Enable Operations | B0h | Non-data | | | | |
| SMART Execute Off-Line Immediate | B0h | Non-data | | | | |
| SMART Read LOG | B0h | PIO data-In | | | | |
| SMART Read Data | B0h | PIO data-In | | | | |
| SMART Read THRESHOLD | B0h | PIO data-In | | | | |
| SMART Return Status | B0h | Non-data | | | | |
| SMART SAVE ATTRIBUTE VALUES | B0h | Non-data | | | | |
| SMART WRITE LOG | B0h | PIO data-out | | | | |
| Host Protected Area Feature Set | | | | | | |

| Read Native Max Address | F8h | Non-data |
|-----------------------------|-----|--------------|
| Set Max Address | F9h | Non-data |
| Set Max Set Password | F9h | PIO data-out |
| Set Max Lock | F9h | Non-data |
| Set Max Freeze Lock | F9h | Non-data |
| Set Max Unlock | F9h | PIO data-out |
| 48-bit Address Feature Set | | |
| Flush Cache Ext | Eah | Non-data |
| Read Sector(s) Ext | 24h | PIO data-in |
| Read DMA Ext | 25h | DMA |
| Read Multiple Ext | 29h | PIO data-in |
| Read Native Max Address Ext | 27h | Non-data |
| Read Verify Sector(s) Ext | 42h | Non-data |
| Set Max Address Ext | 37h | Non-data |
| Write DMA Ext | 35h | DMA |
| Write Multiple Ext | 39h | PIO data-out |
| Write Sector(s) Ext | 34h | PIO data-out |
| NCQ Feature Set | | |
| Read FPDMA Queued | 60h | DMA Queued |
| Write FPDMA Queued | 61h | DMA Queued |
| Other | | |
| Data Set Management | 06h | DMA |
| SEEK | 70h | Non-data |
| | | |



SMART Data Structure

| BYTE | F/V | Description | | | |
|---------|-----|--|--|--|--|
| 0-1 | Х | Revision code | | | |
| 2-361 | Х | Vendor specific | | | |
| 362 | V | Off-line data collection status | | | |
| 363 | х | Self-test execution status byte | | | |
| 364-365 | V | Total time in seconds to complete off-line data collection activity | | | |
| 366 | Х | Vendor specific | | | |
| 367 | F | Off-line data collection capability | | | |
| 368-369 | F | SMART capability | | | |
| 370 | F | Error logging capability 7-1 Reserved 0 1=Device error logging supported | | | |
| 371 | Х | Vendor specific | | | |
| 372 | F | Short self-test routine recommended polling time (in minutes) | | | |
| 373 | F | Extended self-test routine recommended polling time (in minutes) | | | |
| 374 | F | Conveyance self-test routine recommended polling time (in minutes) | | | |
| 375-385 | R | Reserved | | | |
| 386-395 | F | Firmware Version/Date Code | | | |
| 396-397 | F | Reserved | | | |
| 398-399 | V | Reserved | | | |
| 400-406 | V | TS6500 | | | |
| 407-415 | Х | Vendor specific | | | |
| 416 | F | Reserved | | | |
| 417 | F | Program/write the strong page only | | | |
| 418-419 | V | Number of spare block | | | |
| 420-423 | V | Average Erase Count | | | |
| 424-510 | Х | Vendor specific | | | |
| 511 | V | Data structure checksum | | | |

F = content (byte) is fixed and does not change.

V= content (byte) is variable and may change depending on the state of the device or the commands executed by the device.

X= content (byte) is vendor specific and may be fixed or variable.

R= content (byte) is reserved and shall be zero.



SMART Attributes

| Attribute ID (hex) | | | Raw Attri | Attribute Name | | | |
|-----------------------|-----|-----|-----------|----------------|----|----|--|
| 01 | MSB | 00 | 00 | 00 | 00 | 00 | Read Error Rate |
| 05 | LSB | MSB | 00 | 00 | 00 | 00 | Reallocated sectors count |
| 09 | LSB | - | - | MSB | 00 | 00 | Reserved |
| 0C | LSB | MSB | 00 | 00 | 00 | 00 | Power Cycle Count |
| A0 | LSB | - | - | MSB | 00 | 00 | Uncorrectable sectors count when read/write |
| A1 | LSB | MSB | 00 | 00 | 00 | 00 | Number of valid spare blocks |
| A3 | LSB | MSB | 00 | 00 | 00 | 00 | Number of initial invalid blocks |
| A4 | LSB | - | - | MSB | 00 | 00 | Total erase count |
| A5 | LSB | - | - | MSB | 00 | 00 | Maximum erase count |
| A6 | LSB | - | - | MSB | 00 | 00 | Minimum erase count |
| A7 | LSB | - | - | MSB | 00 | 00 | Average erase count |
| C0 | LSB | MSB | 00 | 00 | 00 | 00 | Power-off retract Count |
| C2 | MSB | 00 | 00 | 00 | 00 | 00 | Controlled temperature |
| C3 | LSB | - | - | MSB | 00 | 00 | Hardware ECC recovered |
| C4 | LSB | - | - | MSB | 00 | 00 | Reallocation event count |
| C7 | LSB | MSB | 00 | 00 | 00 | 00 | UltraDMA CRC Error Count |
| F1 | LSB | - | - | MSB | 00 | 00 | Total LBA written (each write unit = 32MB) |
| F2 | LSB | - | - | MSB | 00 | 00 | Total LBA read (each read unit = 32MB) |

The following table shows the vendor specific data in byte 2 to 361 of the 512-byte SMART data



| Revision History | | | | | |
|------------------|------------|---|--|--|--|
| Version | Date | Modification Content | | | |
| V1.0 | 2014/06/04 | Initial Release | | | |
| V1.1 | 2014/08/04 | Improve TS512GMTS800 performance | | | |
| V1.2 | 2014/10/14 | Update performance | | | |
| V1.3 | 2015/01/08 | Update performance / power consumption / package dimensions | | | |

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